

MINISTRY OF SUPPLY (S.R.D.E.)

Specification MOS/CV575/Issue 4 Dated:- 3.7.46 To be read in conjunction with K1001 ignoring clauses:- 5.2 and 5.8.	<table border="1"> <tr> <th colspan="2"><u>SECURITY</u></th></tr> <tr> <th><u>Specification</u></th><th><u>Valve</u></th></tr> <tr> <td>Restricted</td><td>Restricted</td></tr> </table>	<u>SECURITY</u>		<u>Specification</u>	<u>Valve</u>	Restricted	Restricted
<u>SECURITY</u>							
<u>Specification</u>	<u>Valve</u>						
Restricted	Restricted						

—————> indicates a change

<u>TYPE OF VALVE:-</u> High Vacuum full wave rectifier			<u>MARKING</u>		
<u>CATHODE:-</u> Directly heated			See K1001/4		
<u>ENVELOPE:-</u> Glass-unmetallised					
<u>PROTOTYPE:-</u> 5U4G					
<u>RATING</u>			<u>BASE</u> See K1001/A1/D1		
			M dimension (v) applies		
			<u>IO</u>		
			<u>Note</u>		
			<u>Pin</u>		
			<u>Electrode</u>		
Filament voltage	(V)	5.0	1	No connection	
Nominal filament current	(A)	3.0	2	Filament	
Max. applied R.M.S. voltage	(V)	450	3	Pin omitted	
Max. working peak inverse voltage	(V)	1200	4	Anode	
Max. no load peak inverse voltage	(V)	1500	5	Pin omitted	
Max. mean D.C. rectified current	(mA)	225	6	Anode	
Max. peak anode current	(mA)	675	7	Pin omitted	
Max. reservoir condenser	(uF)	16	8	Filament	
Min. limiting resistance per anode introduced externally	(ohms)	75			
(Ratings apply to condenser input filter and 50 c.p.s. supply)			<u>DIMENSIONS</u>		
			See K1001/A1/D1		
			<u>Dimension</u>		
			<u>Min.</u>		
			<u>Max.</u>		
			A mm		
			-		
			136		
			B mm		
			-		
			53		

TESTS

To be performed in addition to those applicable in K1001.

	Test conditions		Test	<u>Limits</u>		No. tested
				Min.	Max.	
a	Vf	Va	If (A)	-	3.3	100% or S
	5.0 A.C.	-				
b	5.0 A.C.	60 D.C. max.	Ia (mA) Note 1	200	-	100%
c	5.0 A.C.	Input voltage 450-0-450 R.M.S. frequency 50 c.p.s. D.C. load 225 mA Reservoir condenser 4 uF. Effective resistance per anode introduced externally 75 ohms.	<u>Load Test</u> Output voltage. Run 1 minute Reject for softness or persistent flushover.	420	-	100%

NOTES

1. Test to be applied to each anode.